

# **60V P-Channel MOSFET**

#### Features

-60V/50A,

 $R_{DS(ON)}$  < 25m $\Omega$  @  $V_{GS}$ = - 10V

 $R_{DS(ON)} < 35m\Omega$  @  $V_{GS}$ = - 4.5V

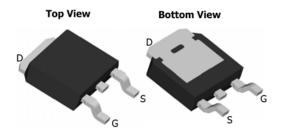
Lead Free Available (RoHS Compliant)

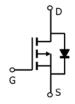
## General Description

The FS2243 combines advanced trench MOSFET technology with a low resistance package to provide extremely low  $R_{\rm DS(ON)}$ . this device is well suited for high current load applications.

## • Pin Configuration

TO252





**TO252** 

### • Absolute Maximum Ratings T<sub>A</sub>=25°C unless otherwise noted

Parameter		Symbol	Maximum	Units	
Drain-Source Voltage		V <sub>DS</sub>	-60	V	
Gate-Source Voltage		V <sub>GS</sub>	±20	7	
Continuous Drain Current	T <sub>A</sub> =25°C		-50	А	
	T <sub>A</sub> =70°C	I <sub>D</sub>	-35		
Pulsed Drain Current note		I <sub>DM</sub>	-150	]	
Avalanche energy L=1mH <sup>note</sup>		E <sub>AS</sub> , E <sub>AR</sub>	722	mJ	
Power Dissipation note	T <sub>A</sub> =25°C	D	50	w	
	T <sub>A</sub> =70°C	→ P <sub>D</sub>	25		
Junction and Storage Temperature Range		T <sub>J</sub> , T <sub>STG</sub>	-55 to 150	°C	

Thermal Characteristics								
Parameter		Symbol	Тур	Max	Units			
Maximum Junction-to-Ambient <sup>A</sup>	t ≤ 10s	В	17	26	°C/W			
Maximum Junction-to-Ambient AD	Stoody State	$R_{ heta JA}$	40	50				
Maximum Junction-to-Lead	Steady-State	$R_{ heta JL}$	2.5	3				

#### Note:

- 1. Repetitive Rating: Pulse width limited by maximum junction temperature.
- 2. Surface Mounted on FR4 Board,  $t \le 10$  sec. Pulse Test: Pulse Width  $\le 300\,\mu$  s, Duty Cycle  $\le 2\%$ .
- 3. EAS condition: Tj=25  $^{\circ}$ C,VDD=-30V,VG=-10V,L=1mH,Rg=25  $^{\Omega}$ ,IAS=38A

## • Electrical Characteristics (T<sub>A</sub>=25°C unless otherwise noted)

Symbol	Parameter	Condition	Conditions		Тур	Max	Units
STATIC PA	ARAMETERS					•	•
BV <sub>DSS</sub>	Drain-Source Breakdown Voltage	I <sub>D</sub> =-250μA, V <sub>GS</sub> =0V	I <sub>D</sub> =-250μA, V <sub>GS</sub> =0V				V
I <sub>DSS</sub>	Zero Gate Voltage Drain Current	\/ - 40\/ \/ -0	T <sub>A</sub> =25°C		-0.002	-1	uA
		V <sub>DS</sub> =-48V, V <sub>GS</sub> =0	T <sub>A</sub> =55°C			-5	
I <sub>GSS</sub>	Gate-Body leakage current	V <sub>DS</sub> =0V, V <sub>GS</sub> =±20V				±0.1	
$V_{GS(th)}$	Gate Threshold Voltage	V <sub>DS</sub> =VGS I <sub>D</sub> =-250µ	V <sub>DS</sub> =VGS I <sub>D</sub> =-250μA		-2.6	-3.5	V
I <sub>D(ON)</sub>	On state drain current <sup>note</sup>	V <sub>GS</sub> =-10V, V <sub>DS</sub> =-5V	V <sub>GS</sub> =-10V, V <sub>DS</sub> =-5V				Α
R <sub>DS(ON)</sub>	Static Drain-Source On-Resistance	V <sub>GS</sub> =-10V, I <sub>D</sub> =-20A	T <sub>A</sub> =25°C		23	28	mΩ
		V <sub>GS</sub> 10V, I <sub>D</sub> 20A	T <sub>A</sub> =125°C		38		
		V <sub>GS</sub> =-4.5V, I <sub>D</sub> =-10A	V <sub>GS</sub> =-4.5V, I <sub>D</sub> =-10A		30	35	•
<b>g</b> FS	Forward Trans conductance	V <sub>DS</sub> =-10V, I <sub>D</sub> =-20A	V <sub>DS</sub> =-10V, I <sub>D</sub> =-20A		25		S
V <sub>SD</sub>	Diode Forward Voltage	I <sub>S</sub> =-1A,V <sub>GS</sub> =0V			-0.75	-1.2	V
Is	Maximum Body-Diode Continuous Curr	ent			-12	Α	
DYNAMIC	PARAMETERS			•		•	
C <sub>iss</sub>	Input Capacitance		V <sub>GS</sub> =0V, V <sub>DS</sub> =-30V, f=1MHz		6460		pF
C <sub>oss</sub>	Output Capacitance	V <sub>GS</sub> =0V, V <sub>DS</sub> =-30V, f			715		
C <sub>rss</sub>	Reverse Transfer Capacitance	1			546		
R <sub>g</sub>	Gate resistance	V <sub>GS</sub> =0V, V <sub>DS</sub> =0V, f=1MHz			6	10	Ω
SWITCHIN	G PARAMETERS					•	•
Q <sub>g</sub> (10V)	T + 1 0 + 01		V <sub>GS</sub> =-10V, V <sub>DS</sub> =-30V, I <sub>D</sub> =-12A		95.5		
Q <sub>g</sub> (4.5V)	Total Gate Charge	101/11/ 001/			75		nC
Q <sub>gs</sub>	Gate Source Charge	$V_{GS}$ =-10V, $V_{DS}$ =-30V			16		
Q <sub>gd</sub>	Gate Drain Charge				19		
t <sub>D(on)</sub>	Turn-On Delay Time		$V_{GS}$ =-10V, $V_{DS}$ =-30V, $R_L$ =2.5 $\Omega$ ,		15		
t <sub>r</sub>	Turn-On Rise Time	V <sub>GS</sub> =-10V, V <sub>DS</sub> =-30V			17		ns
$t_{D(off)}$	Turn-Off Delay Time	$R_{GEN}$ =3 $\Omega$			40		
t <sub>f</sub>	Turn-Off Fall Time				45		
t <sub>rr</sub>	Body Diode Reverse Recovery Time	I <sub>F</sub> =-12A, dI/dt=100A/μs			50	65	1
Q <sub>rr</sub>	Body Diode Reverse Recovery Charge	I <sub>F</sub> =-12A, dI/dt=100A/μs			59		nC

A: The value of R<sub>BJA</sub> is measured with the device mounted on 1in 2 FR-4 board with 2oz. Copper, in a still air environment with T<sub>A</sub> =25°C. The Power dissipation P<sub>DSM</sub> is based on R<sub>BJA</sub> and the maximum allowed junction temperature of 150°C. The value in any given application depends on the user's specific board design, and the maximum temperature of 175°C may be used if the PCB allows it.

B. The power dissipation  $P_D$  is based on  $T_{J(MAX)}$ =175°C, using junction-to-case thermal resistance, and is more useful in setting the upper dissipation limit for cases where additional heatsinking is used.

C: Repetitive rating, pulse width limited by junction temperature  $T_{J(MAX)}$ =175°C.

D. The R  $_{\text{BJA}}$  is the sum of the thermal impedence from junction to case R  $_{\text{BJC}}$  and case to ambient.

E. The static characteristics in Figures 1 to 6 are obtained using <300  $\mu s$  pulses, duty cycle 0.5% max.

F. These curves are based on the junction-to-case thermal impedence which is measured with the device mounted to a large heatsink, assuming a maximum junction temperature of T\_IMAXY=175°C.

G. The maximum current rating is limited by bond-wires.

H. These tests are performed with the device mounted on 1 in 2 FR-4 board with 2oz. Copper, in a still air environment with T<sub>A</sub>=25°C. The SOA curve provides a single pulse rating.

<sup>\*</sup>This device is guaranteed green after data code 8X11 (Sep 1<sup>ST</sup> 2008).

#### TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS

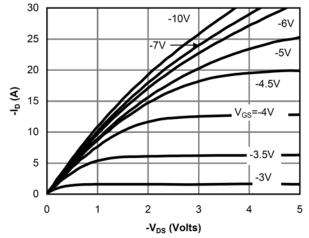


Fig 1: On-Region Characteristics

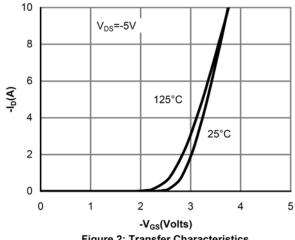


Figure 2: Transfer Characteristics

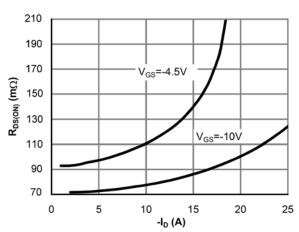


Figure 3: On-Resistance vs. Drain Current and **Gate Voltage** 

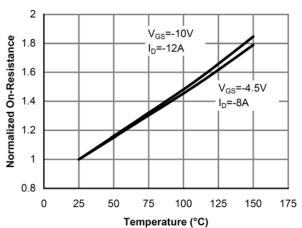


Figure 4: On-Resistance vs. Junction Temperature

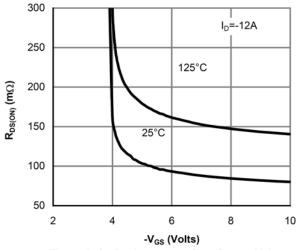


Figure 5: On-Resistance vs. Gate-Source Voltage

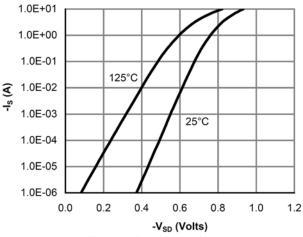
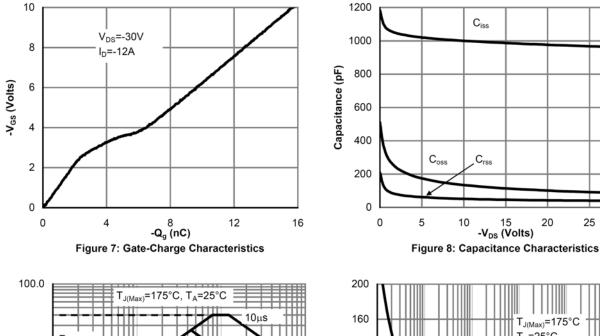


Figure 6: Body-Diode Characteristics

#### TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS



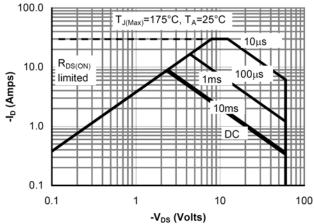


Figure 9: Maximum Forward Biased Safe Operating Area (Note F)

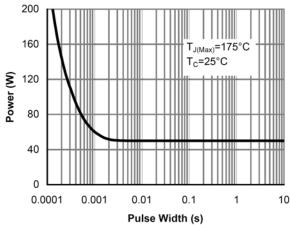


Figure 10: Single Pulse Power Rating Junction-to-Case (Note F)

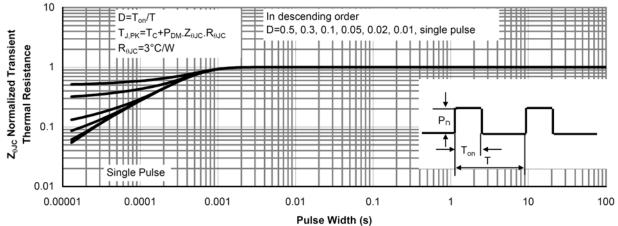


Figure 11: Normalized Maximum Transient Thermal Impedance (Note F)

30

#### TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS

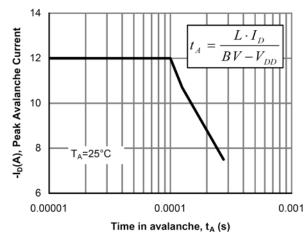


Figure 12: Single Pulse Avalanche capability

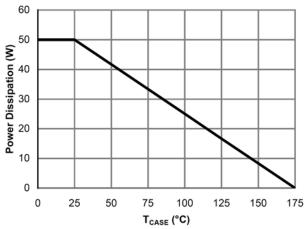


Figure 13: Power De-rating (Note B)

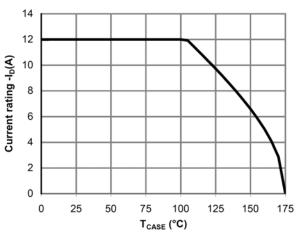


Figure 14: Current De-rating (Note B)

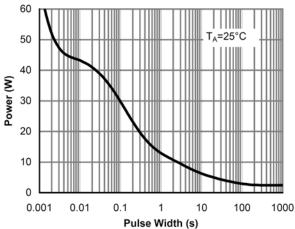


Figure 15: Single Pulse Power Rating Junction-to-Ambient (Note H)

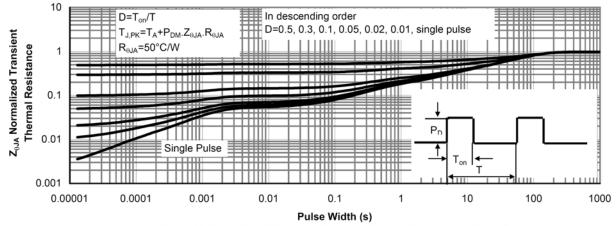
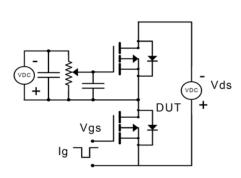
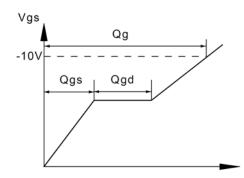


Figure 16: Normalized Maximum Transient Thermal Impedance (Note H)

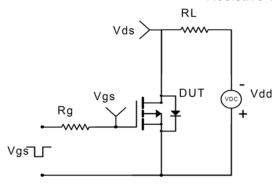
# FS2243

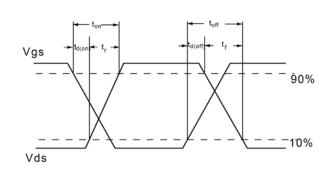
## Gate Charge Test Circuit & Waveform



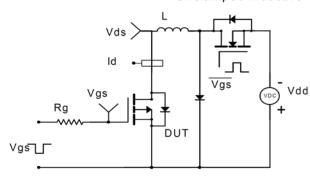


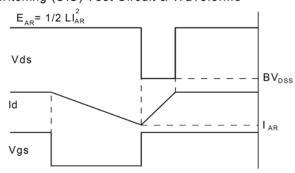
## Resistive Switching Test Circuit & Waveforms





# Unclamped Inductive Switching (UIS) Test Circuit & Waveforms





## Diode Recovery Test Circuit & Waveforms

